

**Search Notes**

Application/Control No.

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Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

HIEDA ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	691	2/8/2006	BT
438	697	2/8/2006	BT
438	700	2/8/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	691	2/8/2006	BT
438	697	2/8/2006	BT
438	700	2/8/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search	2/8/2006	BT